

Integrated analogical signs generator for testing mixed integrated circuits

Abstract

This paper presents the design of a functional block for testing analog and mixed-signal integrated circuits. The objective is that this functional block is embedded into an integrated circuit, IC, to generate the stimuli of the analog functional blocks. The result is a simple block with the ability to generate analog stimuli, as evidenced in the simulations carried out.

Keywords: Integrated circuit, testing, analog and mixed-signal systems